

Title (en)
FREE-STANDING DIAMOND STRUCTURES AND METHODS

Title (de)
FREISTEHENDE DIAMANTENSTRUKTUREN UND VERFAHREN

Title (fr)
STRUCTURES DE DIAMANT AUTOPORTANTES ET PROCEDES

Publication
EP 1601807 A4 20080123 (EN)

Application
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- US 49409503 P 20030812

Abstract (en)
[origin: WO2004072319A2] The present invention is directed in one aspect to methods of making free-standing, internally-supported, three-dimensional objects having an outer surface comprising a plurality of intersecting facets wherein a sub-set of the intersecting facets have a diamond layer of substantially uniform thickness. The diamond layer may be formed by chemical vapor deposition (CVD) over the surface of a substrate that has been fabricated to form a mold defining the sub-set of intersecting facets. A backing layer may be formed over at least a portion of the exposed diamond layer to enhance the rigidity of the layer when the substrate is removed.

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Citation (search report)

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- See references of WO 2004072319A2

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